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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Susumu MIURA et al. Group Art Unit : Not Yet Assigned
Appl. No. : 10/597,768 Examiner : Not Yet Assigned
(National Stage of PCT/JP2005/001838)
I.A. Filed : February 8, 2005 Confirmation No. : 5951
For : WHITE BALANCE ADJUSTING DEVICE AND VIDEO DISPLAY DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
U.S. Patent and Trademark Office
Customer Service Window, Mail Stop AMENDMENT
Randolph Building
401 Dulany Street
Alexandria, VA 22314

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98, Applicants hereby brings to the attention of the Examiner the following information.

The following documents were cited in an International Search Report with respect to International Patent Application No. PCT/JP2005/001838, of which the present application is the U.S. National Stage Application. A copy of the International Search Report has been filed concurrently with the present application and should thus have been brought to the attention of the Examiner.

- (1) Japanese Laid-Open Patent Publication No. HEI 10-145806 A, together with an English language Abstract of the same;
- (2) Japanese Laid-Open Patent Publication No. HEI 11-102428 A, together with an English language Abstract of the same;
- (3) Japanese Laid-Open Patent Publication No. 2003-131654 A, together with an English language Abstract of the same, and patent family member U.S. Patent Application Publication No. 2003/0076312 to YOKOYAMA, which was published on April 24, 2003;
- (4) Japanese Laid-Open Patent Publication No. HEI 4-369155 A, together with an English language Abstract of the same;
- (5) Japanese Laid-Open Patent Publication No. HEI 10-150620 A, together with an English language Abstract of the same; and
- (6) Japanese Laid-Open Patent Publication No. 2001-045527 A, together with an English language Abstract of the same, and patent family member U.S. Patent No. 6,683,616 to YAMAUCHI et al., which issued on January 27, 2004.

The relevance of the documents cited in the International Search Report, as ascertained with respect to the International claims by the International Examiner, is set forth in the International Search Report.

Applicants further submit the following documents.

- (7) Japanese Laid-Open Patent Publication No. SHO 55-025207 A, together with an English language Abstract of the same. Applicants note that this

- document is cited beginning at page 2 of the specification of the above-captioned application;
- (8) Japanese Laid-Open Patent Publication No. 2004-186927 A, together with an English language Abstract of the same, and patent family member U.S. Patent Application Publication No. 2004/0174384 to OCHIAI et al., which was published on September 9, 2004;
 - (9) Japanese Laid-Open Patent Publication No. 2003-244721 A, together with an English language Abstract of the same;
 - (10) Japanese Laid-Open Patent Publication No. SHO 55-041059 A, together with an English language Abstract of the same;
 - (11) Japanese Laid-Open Patent Publication No. SHO 62185489 A, together with an English language Abstract of the same;
 - (12) Japanese Laid-Open Patent Publication No. HEI 4-298189 A, together with an English language Abstract of the same;
 - (13) Japanese Laid-Open Patent Publication No. HEI 5-127620 A, together with an English language Abstract of the same, and patent family member U.S. Patent No. 5,315,378 to SATOU et al., which issued on May 24, 1994;
 - (14) Japanese Laid-Open Patent Publication No. HEI 6-062423 A, together with an English language Abstract of the same;
 - (15) Japanese Laid-Open Patent Publication No. HEI 6-217336 A, together with an English language Abstract of the same;

- (16) Japanese Laid-Open Patent Publication No. HEI 6-269015 A, together with an English language Abstract of the same, and patent family member U.S. Patent No. 5,532,765 to INOUE et al., which issued on July 2, 1996;
- (17) Japanese Laid-Open Patent Publication No. HEI 6-311523 A, together with an English language Abstract of the same;
- (18) Japanese Laid-Open Patent Publication No. HEI 7-064522 A, together with an English language Abstract of the same;
- (19) Japanese Laid-Open Patent Publication No. HEI 7-184218 A, together with an English language Abstract of the same;
- (20) Japanese Laid-Open Patent Publication No. HEI 7-203256 A, together with an English language Abstract of the same, and patent family member U.S. Patent No. 6,160,581 to HIGASHIHARA et al., which issued on December 12, 2000;
- (21) Japanese Laid-Open Patent Publication No. HEI 8-265607 A, together with an English language Abstract of the same;
- (22) Japanese Laid-Open Patent Publication No. HEI 8-336155 A, together with an English language Abstract of the same;
- (23) Japanese Laid-Open Patent Publication No. HEI 10-093854 A, together with an English language Abstract of the same;
- (24) Japanese Laid-Open Patent Publication No. 2000-316173 A, together with an English language Abstract of the same;

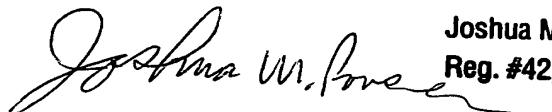
- (25) Japanese Laid-Open Patent Publication No. 2001-024975 A, together with an English language Abstract of the same; and
- (26) Japanese Laid-Open Patent Publication No. 2003-228330 A, together with an English language Abstract of the same.

Further to 37 C.F.R. §1.98 (a)(2)(ii), copies of the U.S. patents and patent application publications are not enclosed herewith. However, if any copy is needed, the Examiner is respectfully requested to contact the undersigned.

Applicants respectfully requests that the Examiner consider the above material and cite the same. Copies of above-noted foreign documents, including the noted English language Abstracts, are attached hereto, and all of the documents are listed on an attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicants with the next official communication in the present application.

Should the Examiner have any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully submitted,
Susumu MIURA et al.


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FORM PTO-1449

U.S. Department of Commerce
Patent and Trademark OfficeAtty. Docket No.
P30425Application No.
10/597,768

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INFORMATION DISCLOSURE STATEMENT
BY APPLICANT
(Use several sheets if necessary)

Applicant
Susumu MIURA et al.I.A. Filing Date
February 8, 2005Group
Not Yet Assigned

U.S. PATENT DOCUMENTS

INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
2003/	0 0 7 6 3 1 2	04/24/03	YOKOYAMA				
	6 6 8 3 6 1 6	01/27/04	YAMAUCHI et al.				
2004/	0 1 7 4 3 8 4	09/09/04	OCHIAI et al.				

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	10	- 1 4 5 8 0 6	05/29/98	JAPAN			
	11	- 1 0 2 4 2 8	04/13/99	JAPAN			
	2003	- 1 3 1 6 5 4	05/09/03	JAPAN			
	4	- 3 6 9 1 5 5	12/21/92	JAPAN			
	10	- 1 5 0 6 2 0	06/02/98	JAPAN			
	2001	- 0 4 5 5 2 7	02/16/01	JAPAN			
	55	- 0 2 5 2 0 7	02/22/80	JAPAN			
	2004	- 1 8 6 9 2 7	07/02/04	JAPAN			
	2003	- 2 4 4 7 2 1	08/29/03	JAPAN			
	55	- 0 4 1 0 5 9	03/22/80	JAPAN			
	62	- 1 8 5 4 8 9	08/13/87	JAPAN			
	4	- 2 9 8 1 8 9	10/21/92	JAPAN			
	5	- 1 2 7 6 2 0	05/25/93	JAPAN			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

1	English Language Abstract of JP 10-145806.
2	English Language Abstract of JP 11-102428.
3	English Language Abstract of JP 2003-131654.
4	English Language Abstract of JP 4-369155.
5	English Language Abstract of JP 10-150620.
6	English Language Abstract of JP 2001-045527.
7	English Language Abstract of JP 55-025207.
8	English Language Abstract of JP 2004-186927.
9	English Language Abstract of JP 2003-244721.
10	English Language Abstract of JP 55-041059.
11	English Language Abstract of JP 62-185489.
12	English Language Abstract of JP 4-298189.
13	English Language Abstract of JP 5-127620.

EXAMINER	DATE CONSIDERED

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. Department of Commerce
Patent and Trademark OfficeAtty. Docket No.
P30425Application No.
10/597,768INFORMATION DISCLOSURE STATEMENT
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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5 3 1 5 3 7 8	05/24/94	SATOU et al.			
	5 5 3 2 7 6 5	07/02/96	INOUE et al.			
	6 1 6 0 5 8 1	12/12/00	HIGASHIHARA et al.			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO
6	- 0 6 2 4 2 3	03/04/94	JAPAN				
6	- 2 1 7 3 3 6	08/05/94	JAPAN				
6	- 2 6 9 0 1 5	09/22/94	JAPAN				
6	- 3 1 1 5 2 3	11/04/94	JAPAN				
7	- 0 6 4 5 2 2	03/10/95	JAPAN				
7	- 1 8 4 2 1 8	07/21/95	JAPAN				
7	- 2 0 3 2 5 6	08/04/95	JAPAN				
8	- 2 6 5 6 0 7	10/11/96	JAPAN				
8	- 3 3 6 1 5 5	12/17/96	JAPAN				
10	- 0 9 3 8 5 4	04/10/98	JAPAN				
2000	- 3 1 6 1 7 3	11/14/00	JAPAN				
2001	- 0 2 4 9 7 5	01/26/01	JAPAN				
2003	- 2 2 8 3 3 0	08/15/03	JAPAN				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

14	English Language Abstract of JP 6-062423.
15	English Language Abstract of JP 6-217336.
16	English Language Abstract of JP 6-269015.
17	English Language Abstract of JP 6-311523.
18	English Language Abstract of JP 7-064522.
19	English Language Abstract of JP 7-184218.
20	English Language Abstract of JP 7-203256.
21	English Language Abstract of JP 8-265607.
22	English Language Abstract of JP 8-336155.
23	English Language Abstract of JP 10-093854.
24	English Language Abstract of JP 2000-316173.
25	English Language Abstract of JP 2001-024975.
26	English Language Abstract of JP 2003-228330.

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